

FORM PTO-1449 (Modified)		ATTY. DOCKET NO.	SERIAL NO.
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(Use several sheets if necessary)		APPLICANTS Robertsson	
		FILING DATE September 21, 2006	GROUP

Examiner Initial		Document No.	Date	Patentee
	AA	2003/125880 A1	07/03/03	Fokkema
	AB	6,026,058	02/15/00	Thomas
	AC	6,101,408	08/08/00	Craine
	AD	6,101,448	08/08/00	Ikelle et al
	AE	6,446,009 B1	09/03/02	Baeten et al
	AF	6,668,228 B1	12/23/03	Özbek et al

		Document No.	Date	Country	Translation Yes No
	AG	2,381,314 A	04/30/03	GB	
	AH	01/53854 A1	07/26/01	WO	
	AI	2004/029662 A1	04/08/04	WO	

	AJ	Amundsen 'Elimination of free-surface related multiples without need of the source wavelet' Geophysics, vol.66 (1), 2001, pp327-341
	AK	Amundsen et al 'Multiple attenuation and P/S splitting of multicomponent OBC data at a heterogenous sea floor' Wave Motion, 32, 2000, pp67-78
	AL	Muijs et al 'Data-driven adaptive decomposition of multicomponent seabed readings' 73 rd Annual International Meeting: Society of Exploration Geophysicists, Dallas 2003
	AM	Osen et al 'Towards optimal spatial filters for multiple attenuation and P/S splitting of OBC data'. EAGE 60 th Conference & Technical Exhibition, Germany, 8-12 June 1998, 1-29, Geophysical Division

	AN	<p>Roesten et al 'Optimal non-recursive and recursive spatial filters for de-multiple of OBS data'</p> <p>72nd International Meeting: Society of Exploration Geophysicists, Salt Lake City 2002</p>
	AO	<p>Schalkwijk et al 'Application of two-step decomposition to multi-component ocean-bottom data: theory and case study'</p> <p>Journal of Seismic Exploration, vol.8, 1999, pp261-278</p>
	AP	<p>Van Manen et al 'Decomposition and calibration of multi-component data in the common shot domain'</p> <p>EAGE 66th Conference & Exhibition, France, 7-10 June 2004, D026</p>
	AQ	<p>Vermeer '3D symmetric sampling', Seismic Acquisition 3: 3-D Data Acquisition SA3.1 64th Annual International Meeting: Society Of Exploration Geophysicists, 1994, pp906-909</p>

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

1. The attached cited information should not be construed as an admission that any of the above items are prior art to the subject invention.
2. This is not a representation that a search has been made.